

ハイスピード CMOS ロジック、非反転型および反転型、スリー・ステート出力のヘキサ・バッファ / ライン・ドライバ

1 特長

- バッファ付き入力
- 大電流バス・ドライバ出力
- t_{PLH} , t_{PHL} = 8ns の標準伝搬遅延 (V_{CC} = 5V, C_L = 15pF, T_A = 25°C)
- ファンアウト (全温度範囲にわたって)
 - 標準出力: 10 の LSTTL 負荷
 - バス・ドライバ出力: 15 の LSTTL 負荷
- 広い動作温度範囲: -55°C ~ 125°C
- 平衡な伝搬遅延と遷移時間
- LSTTL ロジック IC に比べて消費電力を大幅削減
- HC タイプ
 - 2V ~ 6V で動作
 - 優れたノイズ耐性: V_{CC} に対して N_{IL} = 30%, N_{IH} = 30% (V_{CC} = 5V 時)
- HCT タイプ
 - 4.5V ~ 5.5V で動作
 - LSTTL 入力ロジックと直接互換、 V_{IL} = 0.8V (最大値), V_{IH} = 2V (最小値)
 - CMOS 入力互換、 V_{OL} , V_{OH} で $I_L \leq 1\mu A$

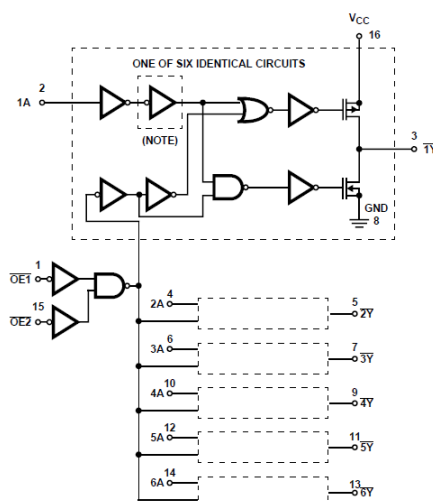
製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称)
CD54HC365	J (CERDIP, 16)	19.56 x 6.92mm
CD54HC366	J (CERDIP, 16)	19.56 x 6.92mm
CD54HCT365	J (CERDIP, 16)	19.56 x 6.92mm
CD74HC365	N (PDIP, 16)	19.30 x 6.35mm
	D (SOIC, 16)	9.90 x 3.90mm
	D (SOIC, 16)	9.90 x 3.90mm
	D (SOIC, 16)	9.90 x 3.90mm
CD74HC366	N (PDIP, 16)	19.30 x 6.35mm
	D (SOIC, 16)	9.90 x 3.90mm
	D (SOIC, 16)	9.90 x 3.90mm
CD74HCT365	N (PDIP, 16)	19.30 x 6.35mm
	D (SOIC, 16)	9.90 x 3.90mm
	D (SOIC, 16)	9.90 x 3.90mm
	D (SOIC, 16)	9.90 x 3.90mm

(1) 利用可能なパッケージについては、このデータシートの末尾にある注文情報を参照してください。

2 概要

'HC365, 'HCT365, 'HC366 シリコン・ゲート CMOS スリー・ステート・バッファは、汎用高速非反転 / 反転バッファです。



HC/HCT365 と HC366 のロジック図 (HC/HCT365 の出力は、1Y、2Y などに示されているものの補完です)

A. インバータは HC/HCT 365 には含まれていません。



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3 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision C (October 2003) to Revision D (July 2022)	Page
• 最新のデータシート規格を反映するように、文書全体の採番、書式設定、表、図、相互参照を更新.....	1

4 Pin Configuration and Functions

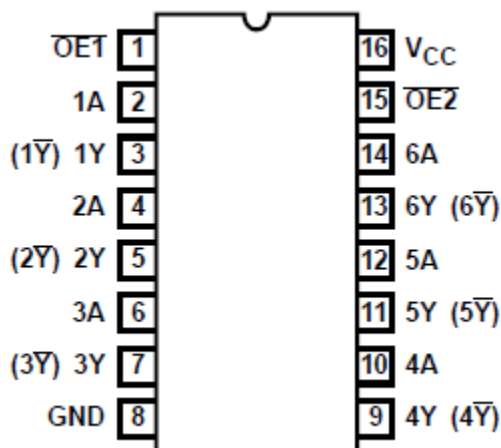


图 4-1. CD54HC365, CD54HCT365, CD54HC366 (CERDIP) CD74HC365, CD74HCT365, CD74HC366 (PDIP, SOIC) Top View

表 4-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME		
1	OE1	I	Output Enable 1, Active Low
2	1A	I	1A Input
3	1Y	O	1Y Output
4	2A	I	2A Input
5	2Y	O	2Y Output
6	3A	I	3A Input
7	3Y	O	3Y Output
8	GND	—	Ground Pin
9	4Y	O	4Y Output
10	4A	I	4A Input
11	5Y	O	5Y Output
12	5A	I	5A Input
13	6Y	O	6Y Output
14	6A	I	6A Input
15	OE2	I	Output Enable 2, Active Low
16	VCC	—	Power Pin

(1) Signal Types: I = Input, O = Output, I/O = Input or Output.

5 Specifications

5.1 Absolute Maximum Ratings⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	DC supply voltage		-0.5	7	V
I _{IK}	DC input diode current	For V _I < -0.5 V or V _I > V _{CC} + 0.5 V		±20	mA
I _{OK}	DC output diode current	For V _O < -0.5 V or V _O > V _{CC} + 0.5 V		±20	mA
I _O	DC drain current, per output	For -0.5 V < V _O < V _{CC} + 0.5 V		±35	mA
I _O	DC output source or sink current per output pin	For V _O > -0.5 V or V _O < V _{CC} + 0.5 V		±25	mA
I _{CC}	DC V _{CC} or ground current			±50	mA
T _J	Maximum junction temperature			150	°C
T _{stg}	Maximum storage temperature range		-65	150	°C
	Maximum lead temperature (soldering 10s)SOIC - lead tips only			300	°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Operating Conditions

			MIN	MAX	UNIT
V _{CC}	Supply voltage range	HC Types	2	6	V
		HCT Types	4.5	5.5	V
V _I , V _O	DC input or output voltage		0	V _{CC}	V
	Input rise and fall time	2 V		1000	ns
		4.5 V		500	
		6 V		400	
T _A	Temperature range		-55	125	°C

5.3 Thermal Information

THERMAL METRIC		N (PDIP)	D (SOIC)	UNIT
		16 PINS	16 PINS	
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	67	73	°C/W

- (1) The package thermal impedance is calculated in accordance with JESD 51 - 7

5.4 Electrical Characteristics

PARAMETER		TEST CONDITIONS		V _{CC} (V)	25°C			–40°C to 85°C		–55°C to 125°C		UNIT
		V _I (V)	I _O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES												
V _{IH} High level input voltage				2	1.5			1.5		1.5		V
				4.5	3.15			3.15		3.15		
				6	4.2			4.2		4.2		
V _{IL} Low level input voltage				2	0.5			0.5		0.5		V
				4.5	1.35			1.35		1.35		
				6	1.8			1.8		1.8		
V _{OH}	High level output voltage CMOS loads	V _{IH} or V _{IL}	-0.02	2	1.9			1.9		1.9		V
			-0.02	4.5	4.4			4.4		4.4		
			-0.02	6	5.9			5.9		5.9		
	High level output voltage TTL loads		-6	4.5	3.98			3.84		3.7		
			-7.8	6	5.48			5.34		5.2		
V _{OL}	Low level output voltage CMOS loads	V _{IH} or V _{IL}	0.02	2	0.1			0.1		0.1		V
			0.02	4.5	0.1			0.1		0.1		
			0.02	6	0.1			0.1		0.1		
	Low level output voltage TTL loads	6	4.5	0.26			0.33		0.4			
		7.8	6	0.26			0.33		0.4			
I _I	Input leakage current	V _{CC} or GND		6	±0.1			±1		±1		µA
I _{CC}	Quiescent device current	V _{CC} or GND	0	6	8			80		160		µA
I _{OZ}	Three-state leakage current	V _{IH} or V _{IL}	V _O = V _{CC} or GND	6	±0.5			±5		±10		µA
HCT TYPES												
V _{IH} High level input voltage				4.5 to 5.5	2			2		2		V
V _{IL} Low level input voltage				4.5 to 5.5	0.8			0.8		0.8		V
V _{OH}	High level output voltage CMOS loads	V _{IH} or V _{IL}	-0.02	4.5	4.4			4.4		4.4		V
	High level output voltage TTL loads		-4	4.5	3.98			3.84		3.7		
V _{OL}	Low level output voltage CMOS loads	V _{IH} or V _{IL}	0.02	4.5	0.1			0.1		0.1		V
	Low level output voltage TTL loads		4	4.5	0.26			0.33		0.4		
I _I	Input leakage current	V _{CC} or GND	0	5.5	±0.1			±1		±1		µA
I _{CC}	Quiescent device current	V _{CC} or GND	0	5.5	8			80		160		µA
ΔI _{CC}	Additional supply current per input pin: 1 Unit Load ⁽¹⁾	V _{CC} - 2.1		4.5 to 5.5	100 360			450		490		µA
I _{OZ}	Three-state leakage current	V _{IL} or V _{IH}	V _O = V _{CC} or GND	5.5	±0.5			±5		±10		µA

(1) For dual-supply systems theoretical worst case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8 mA

5.5 HCT Input Loading Table

Input	Unit Loads ⁽¹⁾
$\overline{OE}1$	0.6
All others	0.55

(1) Unit Load is ΔI_{CC} limit specified in セクション 5.4, e.g., 360 μA max at 25°C.

5.6 Switching Characteristics

$t_r, t_f = 6$ ns

PARAMETER		TEST CONDITIONS	V _{CC} (V)	25°C		40°C to 85°C	55°C to 125°C	UNIT
				TYP	MAX	MAX	MAX	
HC TYPES								
t _{PLH} , t _{PHL}	Propagation delay, data to outputs HC/HCT 365	C _L = 50 pF	2	105	130	160	ns	
			4.5	21	26	32	ns	
			6	18	22	27	ns	
		C _L = 15 pF	5	8			ns	
t _{PLH} , t _{PHL}	Propagation delay, data to outputs HC 366	C _L = 50 pF	2	110	140	165	ns	
			4.5	22	28	33	ns	
			6	19	24	28	ns	
		C _L = 15 pF	5	9			ns	
t _{PLH} , t _{PHL}	Propagation delay time, output enable and disable to outputs	C _L = 50 pF	2	150	190	225	ns	
			4.5	30	38	45	ns	
			6	26	33	38	ns	
		C _L = 15 pF	5	12			ns	
t _{TLH} , t _{THL}	Output transition time	C _L = 50 pF	2	60	75	90	ns	
			4.5	12	15	18	ns	
			6	10	13	15	ns	
C _I	Input capacitance			10	10	10	pF	
C _O	Three-state ouput capacitance			20	20	20	pF	
C _{PD}	Power dissipation capacitance ⁽¹⁾⁽²⁾		5	40			pF	
HCT TYPES								
t _{PLH} , t _{PHL}	Propagation delay, data to outputs HC/HCT 365	C _L = 50 pF	4.5	25	31	38	ns	
							ns	
		C _L = 15 pF	5	9			ns	
							ns	
t _{PLH} , t _{PHL}	Propagation delay, data to outputs HC 366	C _L = 50 pF	4.5	27	34	41	ns	
		C _L = 15 pF	5	11			ns	
t _{PLH} , t _{PHL}	Propagation delay time, output enable and disable to ouputs	C _L = 50 pF	4.5	35	44	53	ns	
		C _L = 15 pF	5	14			ns	
t _{TLH} , t _{THL}	Output transition time	C _L = 50 pF	4.5	12	15	18	ns	
C _{IN}	Input capacitance			10	10	10	pF	
C _O	Three-stage capacitance			20	20	20	pF	
C _{PD}	Power dissipation capacitance ⁽¹⁾⁽²⁾		5	42			pF	

(1) C_{PD} is used to determine the dynamic power consumption, per buffer.

(2) $P_D = V_{CC}^2 f_i (C_{PD} + C_I)$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.

6 Parameter Measurement Information

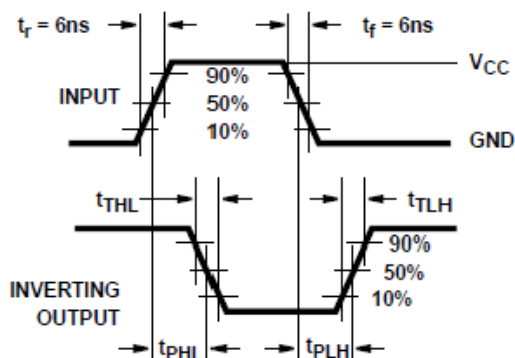


FIG 6-1. HC Transition Times and Propagation Delay Times, Combination Logic

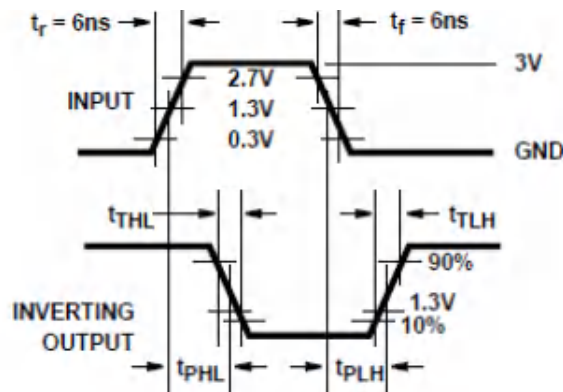


FIG 6-2. HCT Transition Times and Propagation Delay Times, Combination Logic

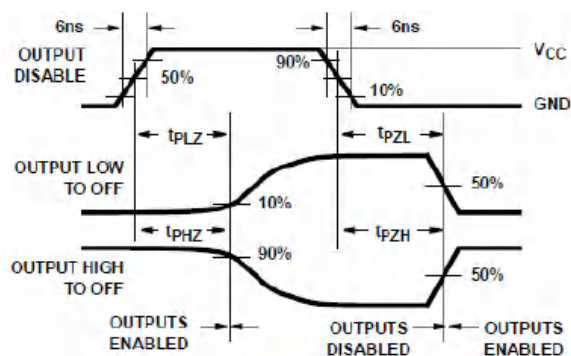


FIG 6-3. HC Three-State Propagation Delay Waveform

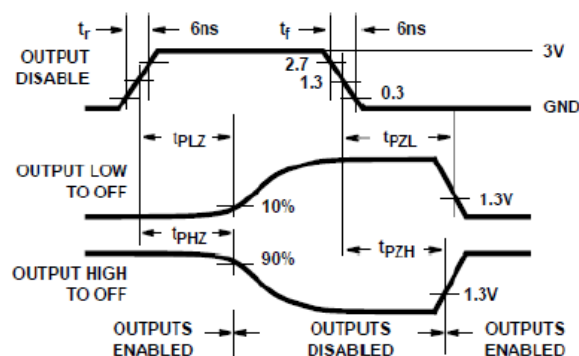
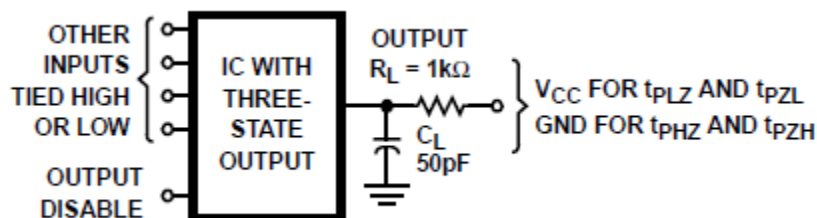


FIG 6-4. HCT Three-State Propagation Delay Waveform



- A. Open drain waveforms t_{PLZ} and t_{PZL} are the same as those for three-state shown on the left. The test circuit is output $R_L = 1\text{ k}\Omega$ to V_{CC} , $C_L = 50\text{ pF}$.

FIG 6-5. HC and HCT Three-State Propagation Delay Test Circuit

7 Detailed Description

7.1 Overview

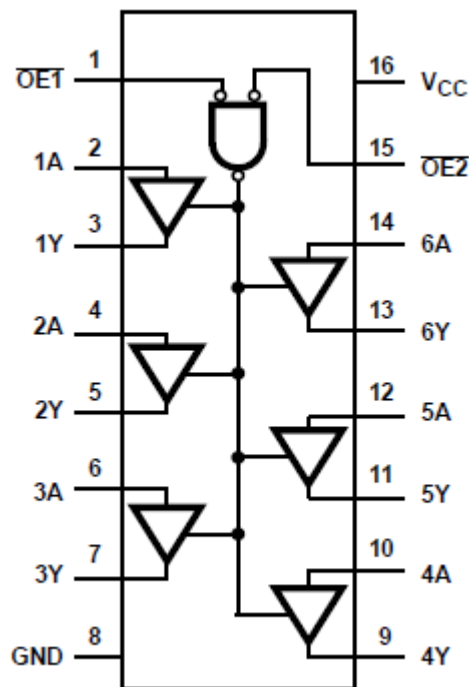
The 'HC365, 'HCT365, and 'HC366 silicon gate CMOS three-state buffers are general purpose high-speed non-inverting and inverting buffers. They have high drive current outputs which enable high speed operation even when driving large bus capacitances. These circuits possess the low power dissipation of CMOS circuitry, yet have speeds comparable to low power Schottky TTL circuits. Both circuits are capable of driving up to 15 low power Schottky inputs.

The 'HC365 and 'HCT365 are non-inverting buffers, whereas the 'HC366 is an inverting buffer. These devices have two three-state control inputs ($\overline{OE}1$ and $\overline{OE}2$) which are NORed together to control all six gates.

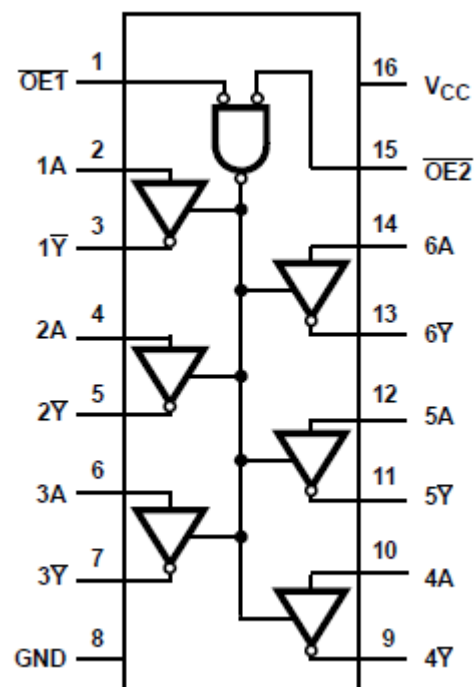
The 'HCT365 logic families are speed, function and pin compatible with the standard LS logic family.

7.2 Functional Block Diagram

Functional Diagrams



HC365, HCT365



HC366

7.3 Device Functional Modes

表 7-1. Function Table

INPUTS ⁽¹⁾			OUTPUTS (Y) ⁽²⁾	
$\overline{OE}1$	$\overline{OE}2$	A	HC/HCT 365	HCT 366
L	L	L	L	H
L	L	H	H	L
X	H	X	Z	Z
H	X	X	Z	Z

(1) H = High Voltage Level, L = Low Voltage Level, X = Don't Care

(2) H = Driving High, L = Driving Low, Z = High Impedance State

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 サポート・リソース

TI E2E™ サポート・フォーラムは、エンジニアが検証済みの回答と設計に関するヒントをエキスパートから迅速かつ直接得ることができる場所です。既存の回答を検索したり、独自の質問をしたりすることで、設計に必要な支援を迅速に得ることができます。

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10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

すべての商標は、それぞれの所有者に帰属します。

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD54HC365F3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8500101EA CD54HC365F3A	Samples
CD54HC366F3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8682801EA CD54HC366F3A	Samples
CD54HCT365F3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HCT365F3A	Samples
CD74HC365E	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC365E	Samples
CD74HC365M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC365M	Samples
CD74HC366E	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC366E	Samples
CD74HC366M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC366M	Samples
CD74HCT365E	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT365E	Samples
CD74HCT365M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HCT365M	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBsolete: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD54HC365, CD54HC366, CD54HCT365, CD74HC365, CD74HC366, CD74HCT365 :

- Catalog : [CD74HC365](#), [CD74HC366](#), [CD74HCT365](#)
- Automotive : [CD74HC366-Q1](#), [CD74HC366-Q1](#)
- Military : [CD54HC365](#), [CD54HC366](#), [CD54HCT365](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC365M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC366M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT365M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC365M96	SOIC	D	16	2500	340.5	336.1	32.0
CD74HC366M96	SOIC	D	16	2500	340.5	336.1	32.0
CD74HCT365M96	SOIC	D	16	2500	356.0	356.0	35.0

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CD74HC365E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC365E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC366E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC366E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT365E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT365E	N	PDIP	16	25	506	13.97	11230	4.32

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - $\triangle C$ Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
 - $\triangle D$ Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
 - E. Reference JEDEC MS-012 variation AC.

J (R-GDIP-T**)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



PINS ** DIM	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



4040083/F 03/03

- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. This package is hermetically sealed with a ceramic lid using glass frit.
 - D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
 - E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

16 PINS SHOWN

PLASTIC DUAL-IN-LINE PACKAGE



PINS ** DIM	14	16	18	20
A MAX	0.775 (19,69)	0.775 (19,69)	0.920 (23,37)	1.060 (26,92)
A MIN	0.745 (18,92)	0.745 (18,92)	0.850 (21,59)	0.940 (23,88)
MS-001 VARIATION	AA	BB	AC	AD



4040049/E 12/2002

NOTES:

- A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
-  Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
 The 20 pin end lead shoulder width is a vendor option, either half or full width.

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郵送先住所 : Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
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